# MSKSEMI 美森科













**ESD** 

TVS

TSS

MOV

GDT

PLED

# TPD4EUSB30DQAR-MS

**Product specification** 





#### **Features**

- 60Watts peak pulse power (tp = 8/20µs)
- Bidirectional configurations
- Solid-state silicon-avalanche technology
- Low clamping voltage
- Low leakage current
- Low capacitance (Cj=0.2pF typ. I/O to I/O)
- IEC 61000-4-2 ±20kV contact ±25kV air
- IEC 61000-4-4 (EFT) 40A (5/50ns)
- IEC 61000-4-5 (Lightning) 4A (8/20µs)

#### **Mechanical Data**

- Molding compound flammability rating: UL94V-0
- Packaging: Tape and Reel
- RoHS/WEEE Compliant

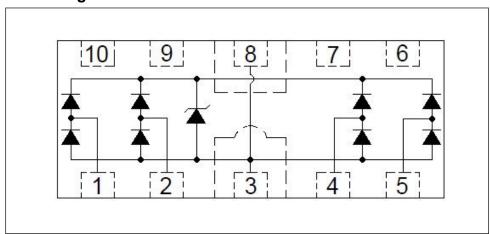
## **Applications**

- USB3.0, USB2.0, Ethernet
- HDMI 2.0, Displayport 1.3,eSATA
- Unified Display interface
- Digital Visual Interface
- High speed serial interface

#### **Reference News**

PACKAGE OUTLINE	Marking
DFN2510-10	.7566V

#### **Schematic & PIN Configuration**



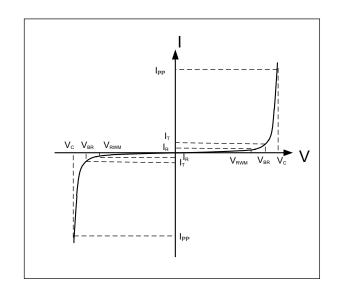


## **Electrical Characteristics**

Parameter	Symbol	Conditions	Min	Typical	Max	Units	
Reverse Stand-Off Voltage	$V_{RWM}$				5.0	V	
Reverse Breakdown Voltage	$V_{BR}$	l₁=1 mA	6.0			V	
Reverse Leakage Current	I <sub>R</sub>	V <sub>RWM</sub> =5V,T=25 ℃			1	μΑ	
Peak Pulse Current	I <sub>PP</sub>	tp =8/20μs			4	А	
Clamping Voltage	Vc	I <sub>PP</sub> =4A,t <sub>p</sub> =8/20μs			15	V	
Junction Capacitance	C <sub>j</sub>	V <sub>R</sub> = 0V, f = 1MHz I/O to I/O		0.2	0.3	pF	
		V <sub>R</sub> = 0V, f = 1MHz I/O to GND		0.4	0.55		

# Electrical Parameters (TA = 25°C unless otherwise noted)

	Parameter			
<b>I</b> PP	MaximumReversePeak Pulse Current			
Vc	Clamping Voltage @ IPP			
VRWM	WorkingPeak Reverse Voltage			
<b>I</b> R	Maximum Reverse Leakage Current @ Vкwм			
V <sub>BR</sub>	Breakdown Voltage @ IT			
lπ	Test Current			



Note: .8/20 µs pulse waveform.



# **Typical Characteristic Curves**

Fig.1 Peak Pulse Power Rating Curve

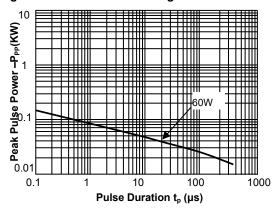


Fig.2 Pulse Derating Curve

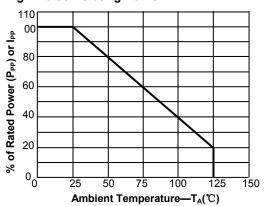


Fig.3 Pulse Waveform-8/20µs

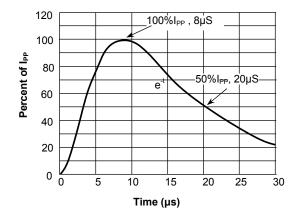
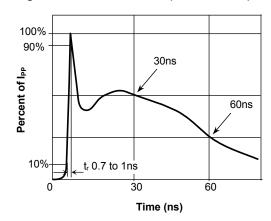
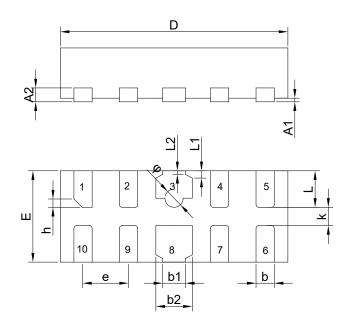


Fig.4 Pulse Waveform-ESD(IEC61000-4-2)





# Dimension (DFN2510-10)





Dimensions in Millimeter							
Symbol	Min.	Nom.	Max.	Symbol	Min.	Nom.	Max.
Α	0.500	0.550	0.600	D	2.450	2.500	2.550
A1	0.00	1	0.05	Е	0.950	1.00	1.050
A2	0.122	0.152	0.200	е	0.450	0.500	0.550
b	0.150	0.200	0.250	h	0.080	0.120	0.150
b1	0.200	0.250	0.300	k	0.150	0.200	0.250
b2	0.350	0.400	0.450	L	0.350	0.400	0.450
L1	0.075 REF		L2	0.05 REF			
φ	0.150	0.200	0.250				

## **REEL SPECIFICATION**

P/N	PKG	QTY
TPD4EUSB30DQAR-MS	DFN2510-10	3000



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